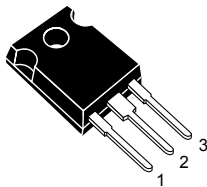
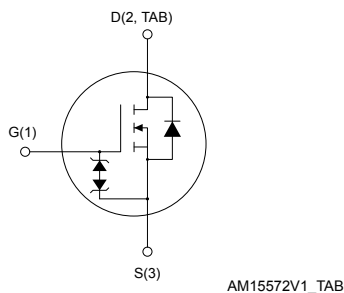


## N-channel 1000 V, 440 mΩ typ., 13 A SuperMESH Power MOSFET in a TO-247 package



TO-247



### Features

| Order code  | $V_{DS}$ | $R_{DS(on)}$ max. | $I_D$ |
|-------------|----------|-------------------|-------|
| STW13NK100Z | 1000 V   | 700 mΩ            | 13 A  |

- 100% avalanche tested
- Extremely high dv/dt capability
- Gate charge minimized
- Zener-protected

### Applications

- Switching applications

### Description

This high-voltage device is a Zener-protected N-channel Power MOSFET developed using the SuperMESH technology by STMicroelectronics, an optimization of the well-established PowerMESH. In addition to a significant reduction in on-resistance, this device is designed to ensure a high level of dv/dt capability for the most demanding applications.



#### Product status link

[STW13NK100Z](#)

#### Product summary

|            |             |
|------------|-------------|
| Order code | STW13NK100Z |
| Marking    | W13NK100Z   |
| Package    | TO-247      |
| Packing    | Tube        |

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

| Symbol         | Parameter                                                                       | Value      | Unit               |
|----------------|---------------------------------------------------------------------------------|------------|--------------------|
| $V_{DS}$       | Drain-source voltage                                                            | 1000       | V                  |
| $V_{GS}$       | Gate-source voltage                                                             | $\pm 30$   | V                  |
| $I_D$          | Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$                | 13         | A                  |
|                | Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$               | 8.2        |                    |
| $I_{DM}^{(1)}$ | Drain current (pulsed)                                                          | 52         | A                  |
| $P_{TOT}$      | Total power dissipation at $T_C = 25\text{ }^{\circ}\text{C}$                   | 350        | W                  |
| ESD            | Gate-source human body model ( $R = 1.5\text{ k}\Omega$ , $C = 100\text{ pF}$ ) | 6          | kV                 |
| $dv/dt^{(2)}$  | Peak diode recovery voltage slope                                               | 4          | V/ns               |
| $T_{stg}$      | Storage temperature range                                                       | -55 to 150 | $^{\circ}\text{C}$ |
| $T_J$          | Operating junction temperature range                                            |            |                    |

1. Pulse width is limited by safe operating area.

2.  $I_{SD} \leq 13\text{ A}$ ,  $di/dt \leq 200\text{ A}/\mu\text{s}$ ,  $V_{DS}(\text{peak}) < V_{(BR)DSS}$ .

**Table 2. Thermal data**

| Symbol     | Parameter                               | Value | Unit                        |
|------------|-----------------------------------------|-------|-----------------------------|
| $R_{thJC}$ | Thermal resistance, junction-to-case    | 0.36  | $^{\circ}\text{C}/\text{W}$ |
| $R_{thJA}$ | Thermal resistance, junction-to-ambient | 50    | $^{\circ}\text{C}/\text{W}$ |

**Table 3. Avalanche characteristics**

| Symbol   | Parameter                                                                                                              | Value | Unit |
|----------|------------------------------------------------------------------------------------------------------------------------|-------|------|
| $I_{AR}$ | Avalanche current, repetitive or not-repetitive (pulse width limited by $T_J$ max.)                                    | 13    | A    |
| $E_{AS}$ | Single pulse avalanche energy (starting $T_J = 25\text{ }^{\circ}\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ ) | 700   | mJ   |

## 2 Electrical characteristics

$T_C = 25\text{ }^{\circ}\text{C}$  unless otherwise specified.

**Table 4. On/off states**

| Symbol        | Parameter                         | Test conditions                                                                              | Min. | Typ. | Max.     | Unit          |
|---------------|-----------------------------------|----------------------------------------------------------------------------------------------|------|------|----------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage    | $I_D = 1\text{ mA}$ , $V_{GS} = 0\text{ V}$                                                  | 1000 | -    | -        | V             |
| $I_{DSS}$     | Zero gate voltage drain current   | $V_{GS} = 0\text{ V}$ , $V_{DS} = 1000\text{ V}$                                             | -    | -    | 1        | $\mu\text{A}$ |
|               |                                   | $V_{GS} = 0\text{ V}$ , $V_{DS} = 1000\text{ V}$ , $T_C = 125\text{ }^{\circ}\text{C}^{(1)}$ | -    | -    | 10       |               |
| $I_{GSS}$     | Gate body leakage current         | $V_{GS} = \pm 20\text{ V}$ , $V_{DS} = 0\text{ V}$                                           | -    | -    | $\pm 10$ | $\mu\text{A}$ |
| $V_{GS(th)}$  | Gate threshold voltage            | $V_{DS} = V_{GS}$ , $I_D = 150\text{ }\mu\text{A}$                                           | 3    | 3.75 | 4.5      | V             |
| $R_{DS(on)}$  | Static drain-source on-resistance | $V_{GS} = 10\text{ V}$ , $I_D = 6.5\text{ A}$                                                | -    | 440  | 700      | m $\Omega$    |

1. Specified by design, not tested in production.

**Table 5. Dynamic**

| Symbol                     | Parameter                     | Test conditions                                                                                                                                  | Min. | Typ. | Max.               | Unit |
|----------------------------|-------------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------|------|------|--------------------|------|
| $C_{iss}$                  | Input capacitance             | $V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GS} = 0\text{ V}$                                                                              | -    | 6000 | -                  | pF   |
| $C_{oss}$                  | Output capacitance            |                                                                                                                                                  | -    | 455  | -                  | pF   |
| $C_{rss}$                  | Reverse transfer capacitance  |                                                                                                                                                  | -    | 100  | -                  | pF   |
| $C_{oss\text{ eq.}}^{(1)}$ | Equivalent output capacitance | $V_{GS} = 0\text{ V}$ , $V_{DS} = 0\text{ to }800\text{ V}$                                                                                      | -    | 227  | -                  | pF   |
| $Q_g$                      | Total gate charge             | $V_{DD} = 800\text{ V}$ , $I_D = 13\text{ A}$ , $V_{GS} = 0\text{ to }10\text{ V}$<br>(see the Figure 14. Test circuit for gate charge behavior) | -    | 190  | 266 <sup>(2)</sup> | nC   |
| $Q_{gs}$                   | Gate-source charge            |                                                                                                                                                  | -    | 30   | -                  | nC   |
| $Q_{gd}$                   | Gate-drain charge             |                                                                                                                                                  | -    | 100  | -                  | nC   |

1.  $C_{oss\text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

2. Specified by design, not tested in production.

**Table 6. Switching times**

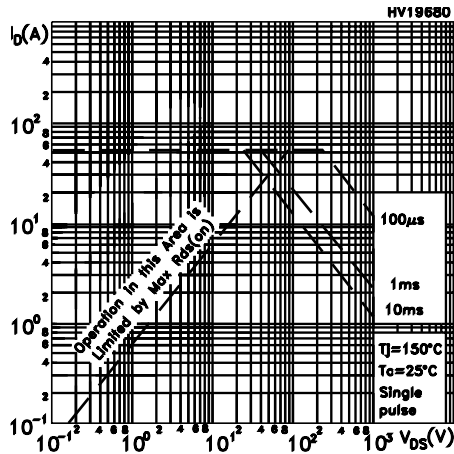
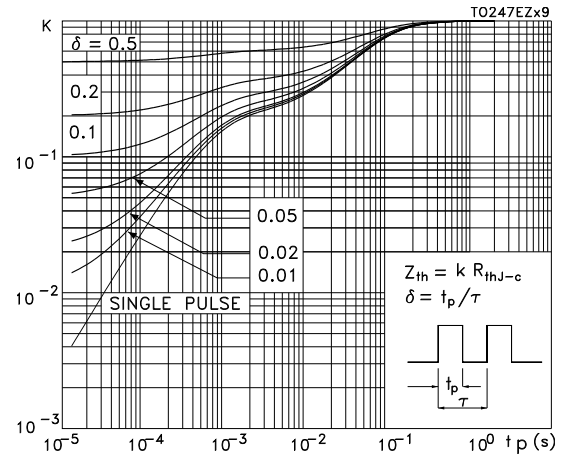
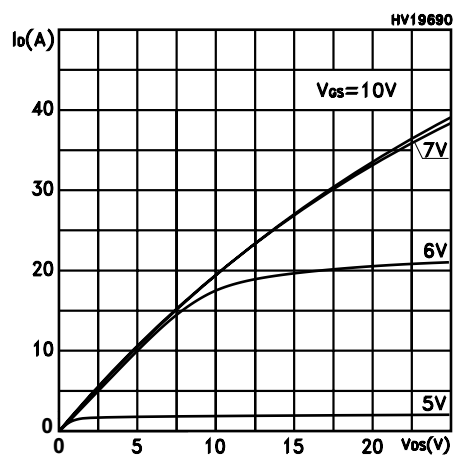
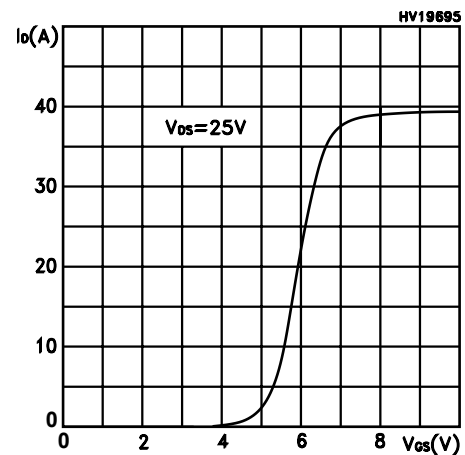
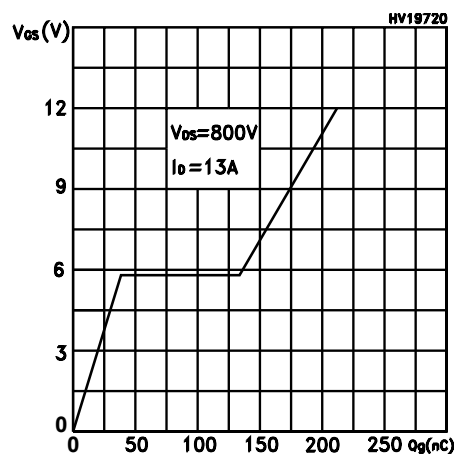
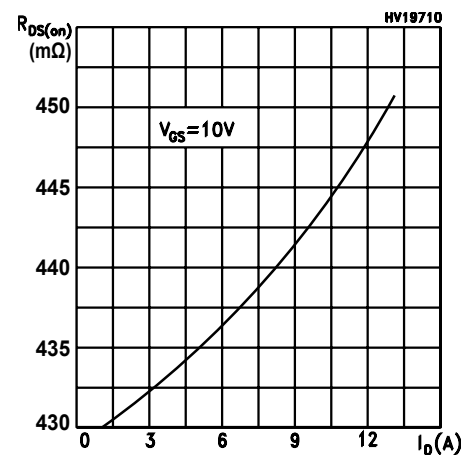
| Symbol       | Parameter           | Test condition                                                                                              | Min. | Typ. | Max. | Unit |
|--------------|---------------------|-------------------------------------------------------------------------------------------------------------|------|------|------|------|
| $t_{d(on)}$  | Turn-on delay time  | $V_{DD} = 500\text{ V}$ , $I_D = 7\text{ A}$ ,<br>$R_G = 4.7\text{ }\Omega$ , $V_{GS} = 10\text{ V}$        | -    | 45   | -    | ns   |
| $t_r$        | Rise time           |                                                                                                             | -    | 35   | -    | ns   |
| $t_{d(off)}$ | Turn-off delay time | (see the Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform) | -    | 145  | -    | ns   |
| $t_f$        | Fall time           |                                                                                                             | -    | 45   | -    | ns   |

**Table 7. Source-drain diode**

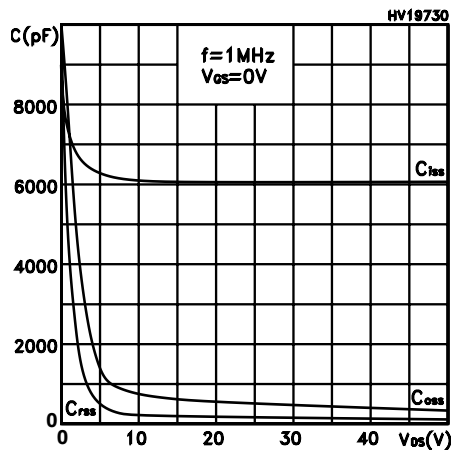
| Symbol          | Parameter                     | Test conditions                                                                                                              | Min. | Typ. | Max. | Unit          |
|-----------------|-------------------------------|------------------------------------------------------------------------------------------------------------------------------|------|------|------|---------------|
| $I_{SD}$        | Source-drain current          |                                                                                                                              | -    | -    | 13   | A             |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) |                                                                                                                              | -    | -    | 52   | A             |
| $V_{SD}^{(2)}$  | Forward on voltage            | $I_{SD} = 13\text{ A}$ , $V_{GS} = 0\text{ V}$                                                                               | -    | -    | 1.6  | V             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 13\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 100\text{ V}$                                     | -    | 820  | -    | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                              | -    | 12.7 | -    | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      | (see the Figure 15. Test circuit for inductive load switching and diode recovery times)                                      | -    | 31   | -    | A             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 13\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 100\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$ | -    | 1050 | -    | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                              | -    | 17.8 | -    | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      | (see the Figure 15. Test circuit for inductive load switching and diode recovery times)                                      | -    | 34   | -    | A             |

1. Pulse width is limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

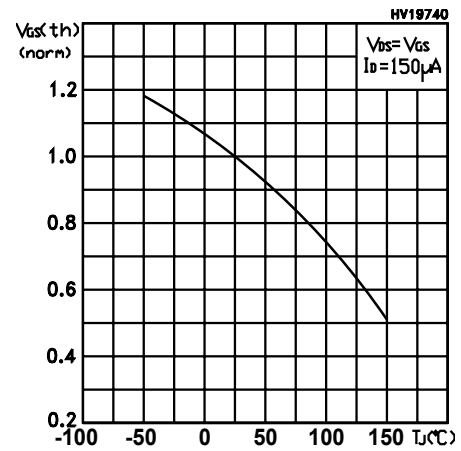
## 2.1 Electrical characteristics (curves)

**Figure 1. Safe operating area**

**Figure 2. Normalized transient thermal impedance**

**Figure 3. Typical output characteristics**

**Figure 4. Typical transfer characteristics**

**Figure 5. Typical gate charge characteristics**

**Figure 6. Typical drain-source on-resistance**


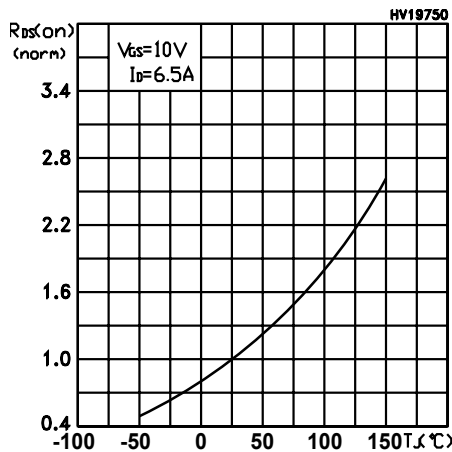
**Figure 7. Typical capacitance characteristics**



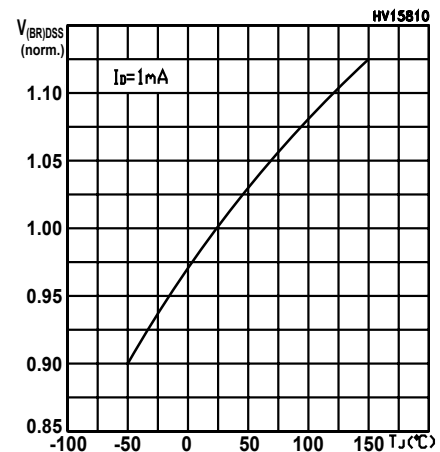
**Figure 8. Normalized gate threshold vs temperature**



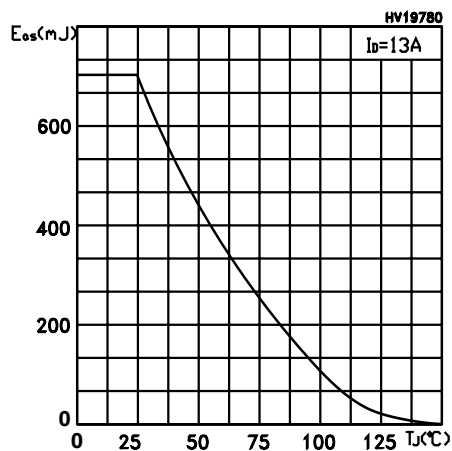
**Figure 9. Normalized on-resistance vs temperature**



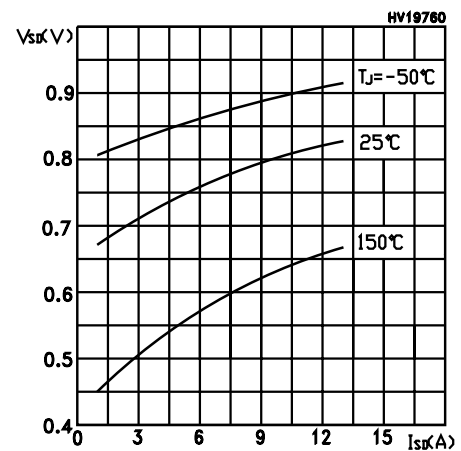
**Figure 10. Normalized breakdown voltage vs temperature**



**Figure 11. Maximum avalanche energy vs temperature**



**Figure 12. Typical reverse diode forward characteristics**



### 3 Test circuits

**Figure 13. Test circuit for resistive load switching times**


AM01468v1

**Figure 14. Test circuit for gate charge behavior**

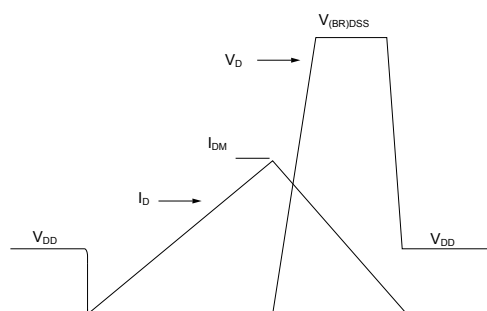

AM01469v1

**Figure 15. Test circuit for inductive load switching and diode recovery times**


AM01470v1

**Figure 16. Unclamped inductive load test circuit**


AM01471v1

**Figure 17. Unclamped inductive waveform**


AM01472v1

**Figure 18. Switching time waveform**

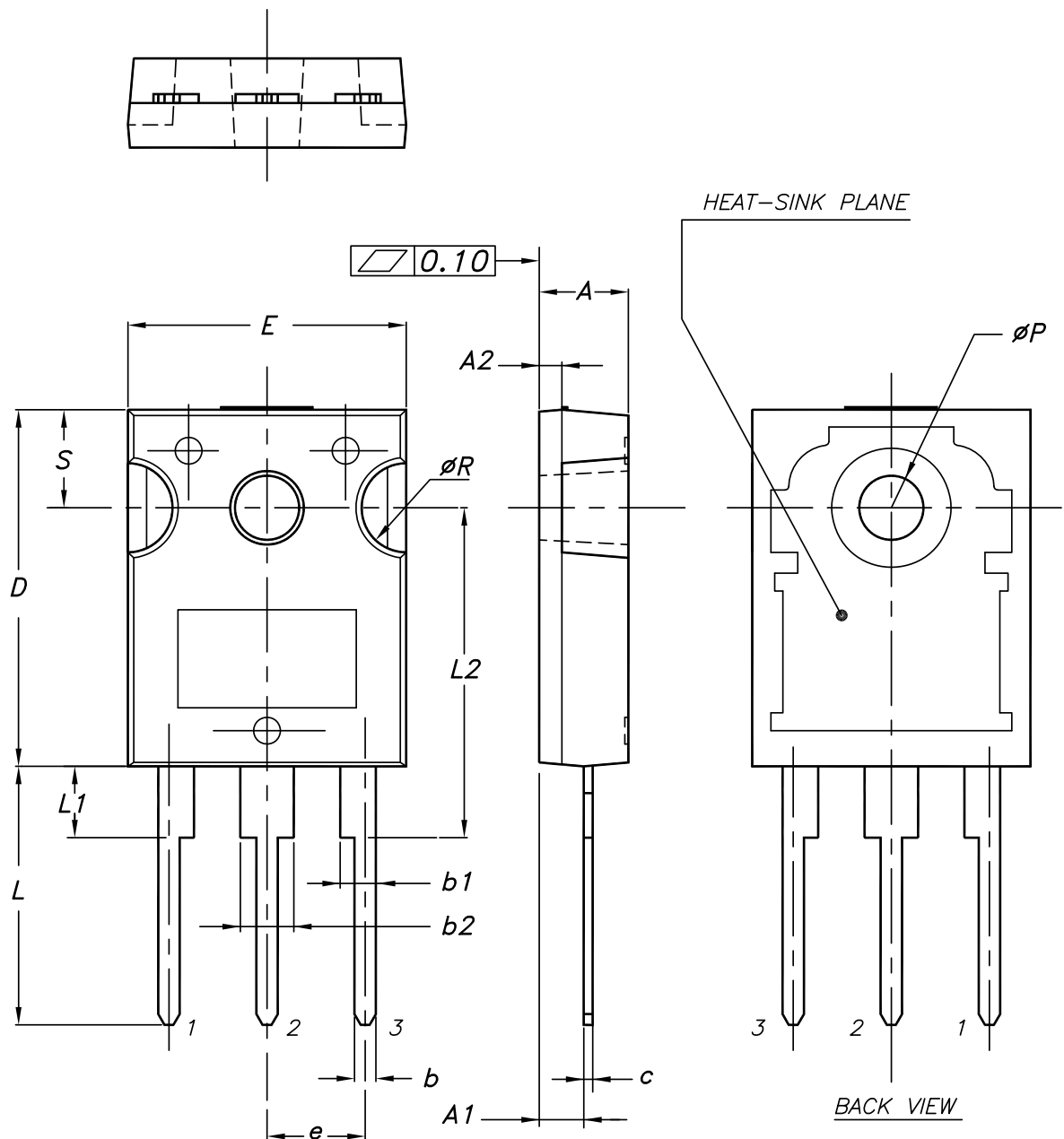

AM01473v1

## 4 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 TO-247 package information

Figure 19. TO-247 package outline



0075325\_11

**Table 8. TO-247 package mechanical data**

| Dim. | mm    |       |       |
|------|-------|-------|-------|
|      | Min.  | Typ.  | Max.  |
| A    | 4.85  |       | 5.15  |
| A1   | 2.20  |       | 2.60  |
| A2   |       | 1.27  |       |
| b    | 1.0   |       | 1.40  |
| b1   | 2.0   |       | 2.40  |
| b2   | 3.0   |       | 3.40  |
| c    | 0.40  |       | 0.80  |
| D    | 19.85 |       | 20.15 |
| E    | 15.45 |       | 15.75 |
| e    | 5.30  | 5.45  | 5.60  |
| L    | 14.20 |       | 14.80 |
| L1   | 3.70  |       | 4.30  |
| L2   |       | 18.50 |       |
| ØP   | 3.55  |       | 3.65  |
| ØR   | 4.50  |       | 5.50  |
| S    | 5.30  | 5.50  | 5.70  |

## Revision history

**Table 9. Document revision history**

| Date        | Revision | Changes                                                                         |
|-------------|----------|---------------------------------------------------------------------------------|
| 22-Jun-2004 | 1        | Target document.                                                                |
| 09-Sep-2004 | 2        | Preliminary document.                                                           |
| 28-Jan-2005 | 3        | Complete version with curves.                                                   |
| 18-Sep-2005 | 4        | <i>Figure 12</i> changed.                                                       |
| 01-Aug-2006 | 5        | New template, no content change.                                                |
| 21-Jan-2026 | 6        | Updated <a href="#">Section 4: Package information</a> .<br>Minor text changes. |



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